



## WBS 3.1.2 - Calorimeter Trigger

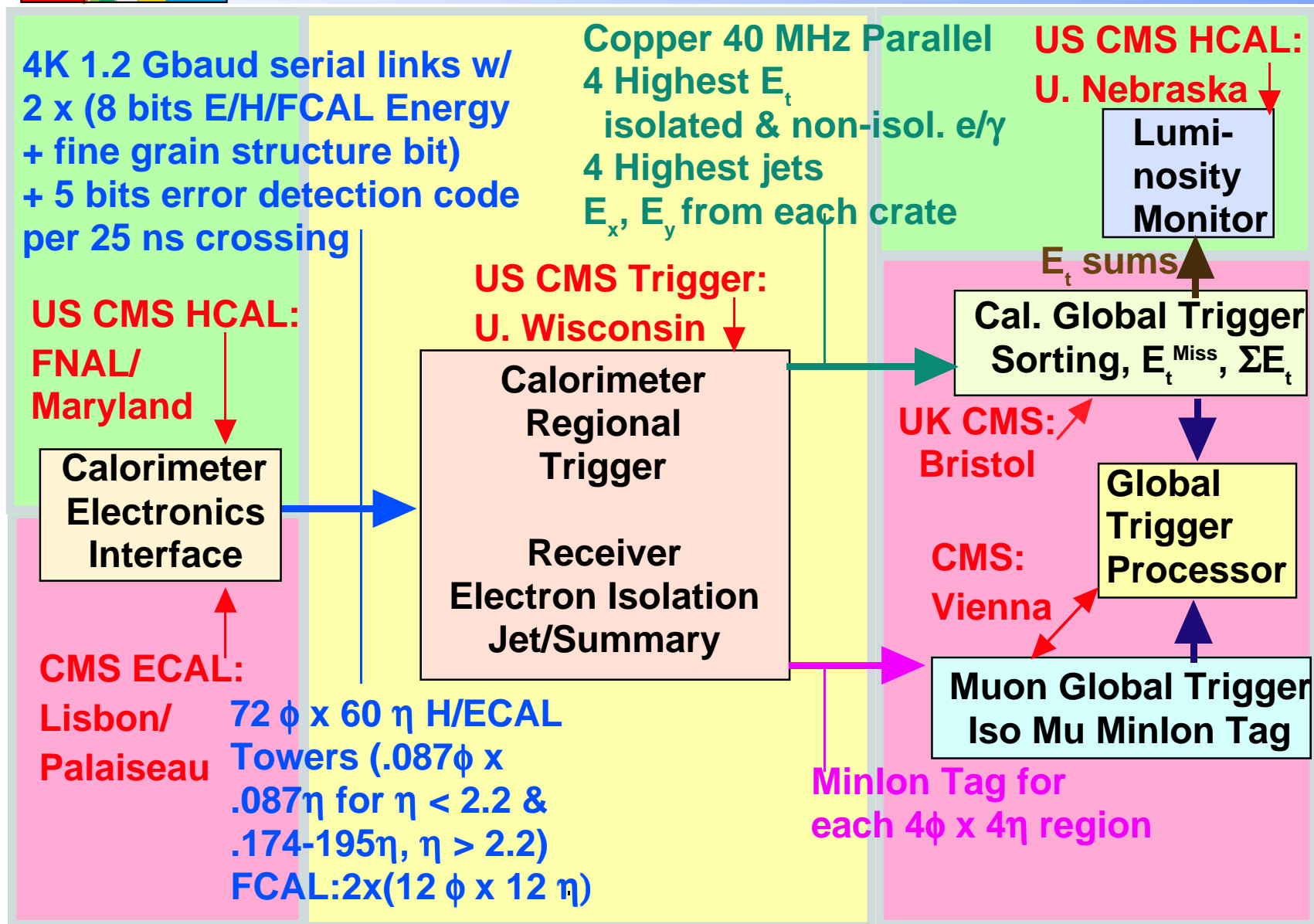
**Sridhara Dasu**

*Level-3 Project Manager  
CMS Calorimeter Trigger Project  
University of Wisconsin*

**DOE/NSF Review  
May 9, 2000**

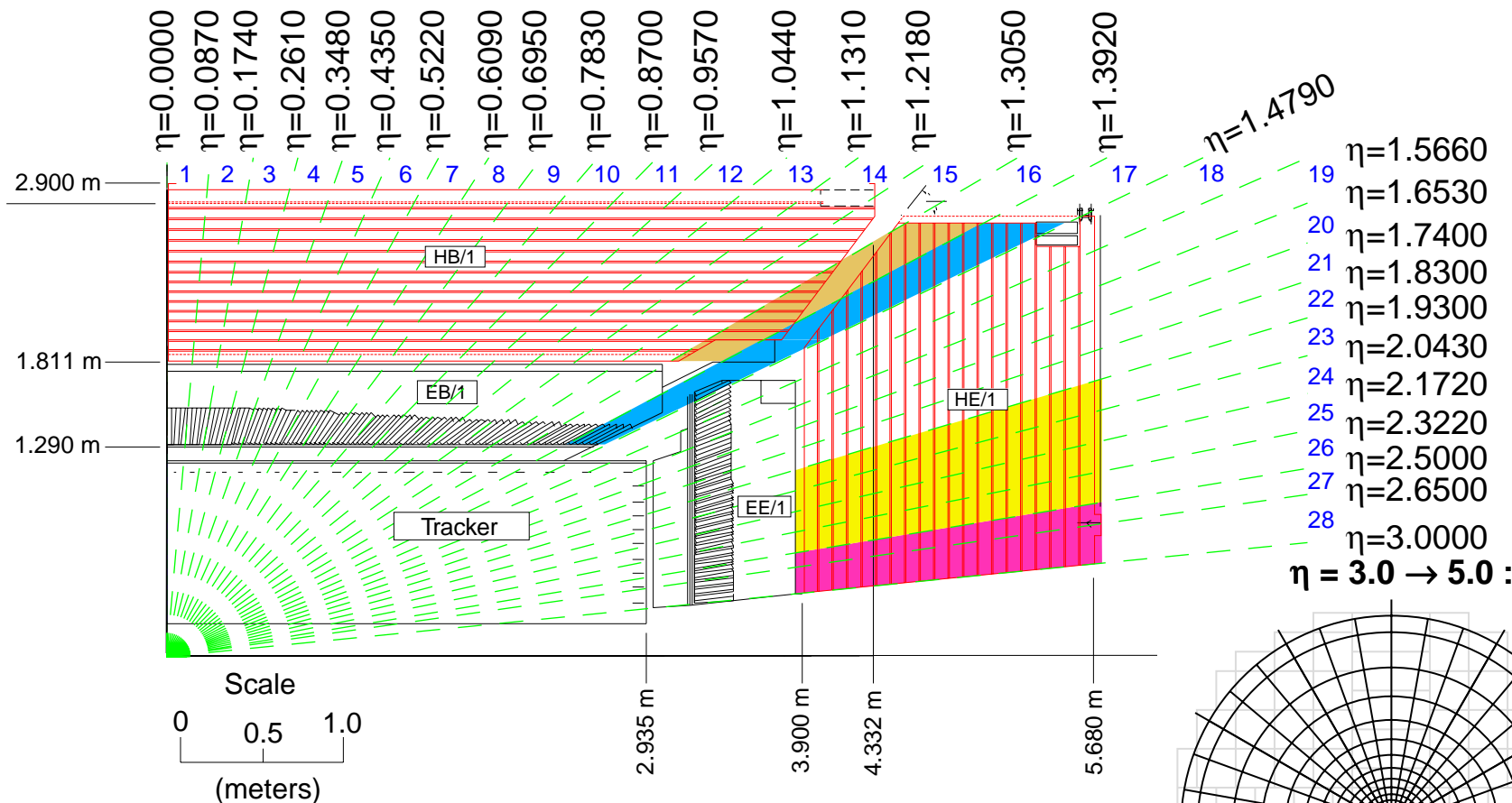


# Calorimeter Trigger Overview





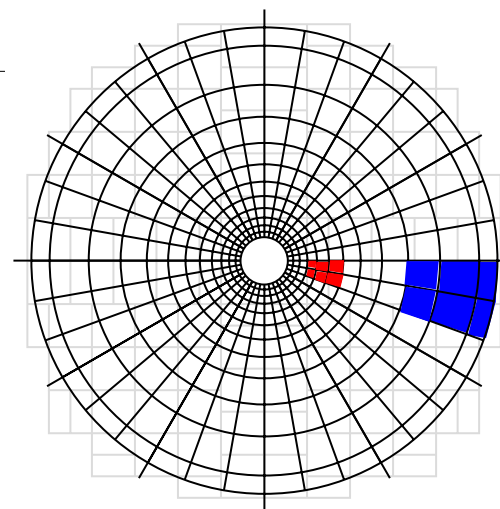
# Calorimeter Trigger Geometry



2 CMS HF Calorimeters mapping onto  
Trigger System HF Crate

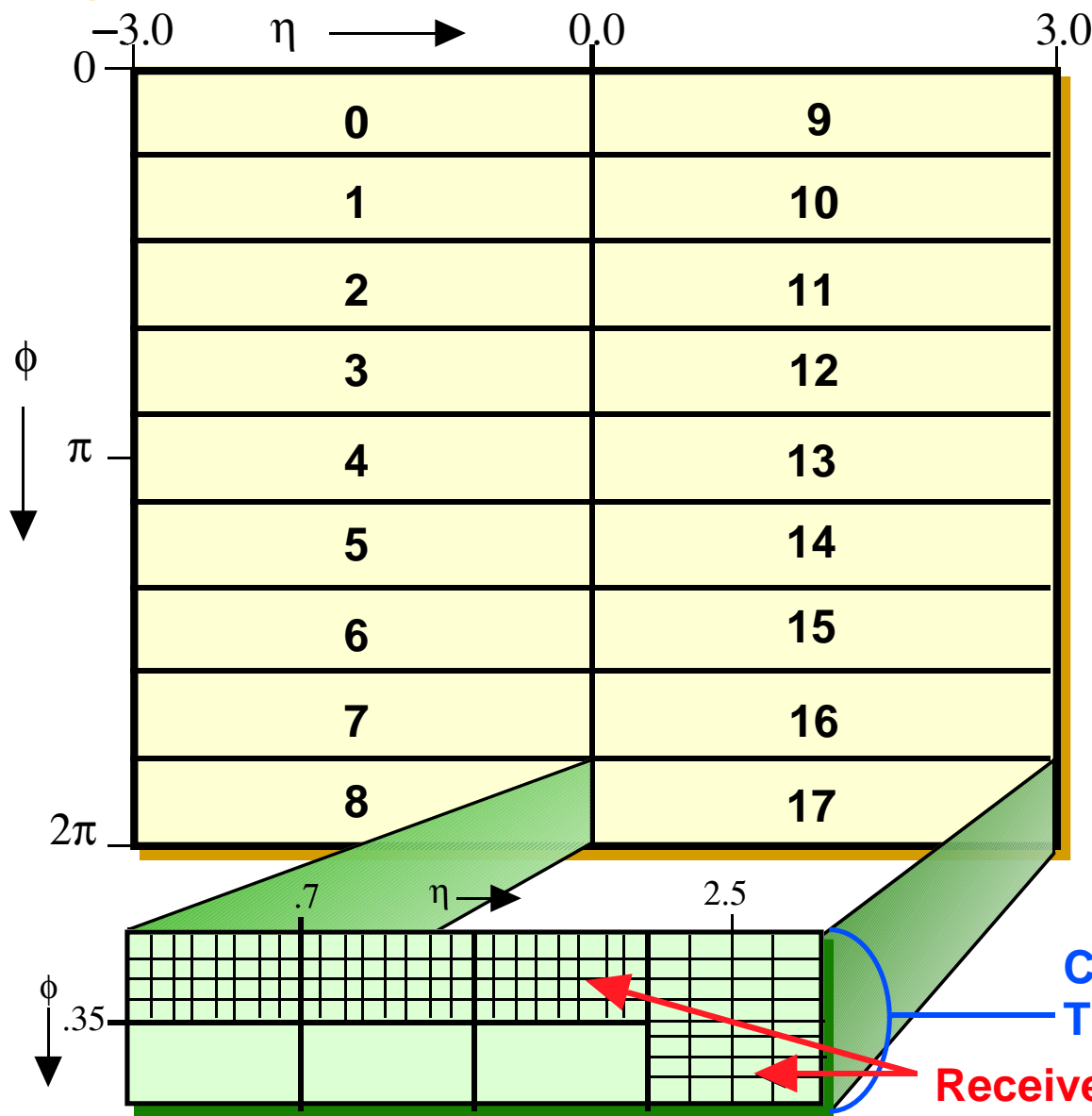
Readout segmentation:  $36\phi \times 12\eta \times 2z \times 2F/B$

Trigger Tower segmentation:  $18\phi \times 4\eta \times 2F/B$





# Cal. Trigger Tower Mapping



18 crates for barrel & endcap calorimeters + 1 for v. forward.

Each crate processes a  $0.7 \phi \times 3.0 \eta$  region.

Each Receiver/Elec. ID card pair typically covers a  $.35 \phi \times 0.7 \eta$  region (modified in high- $\eta$  endcap region)

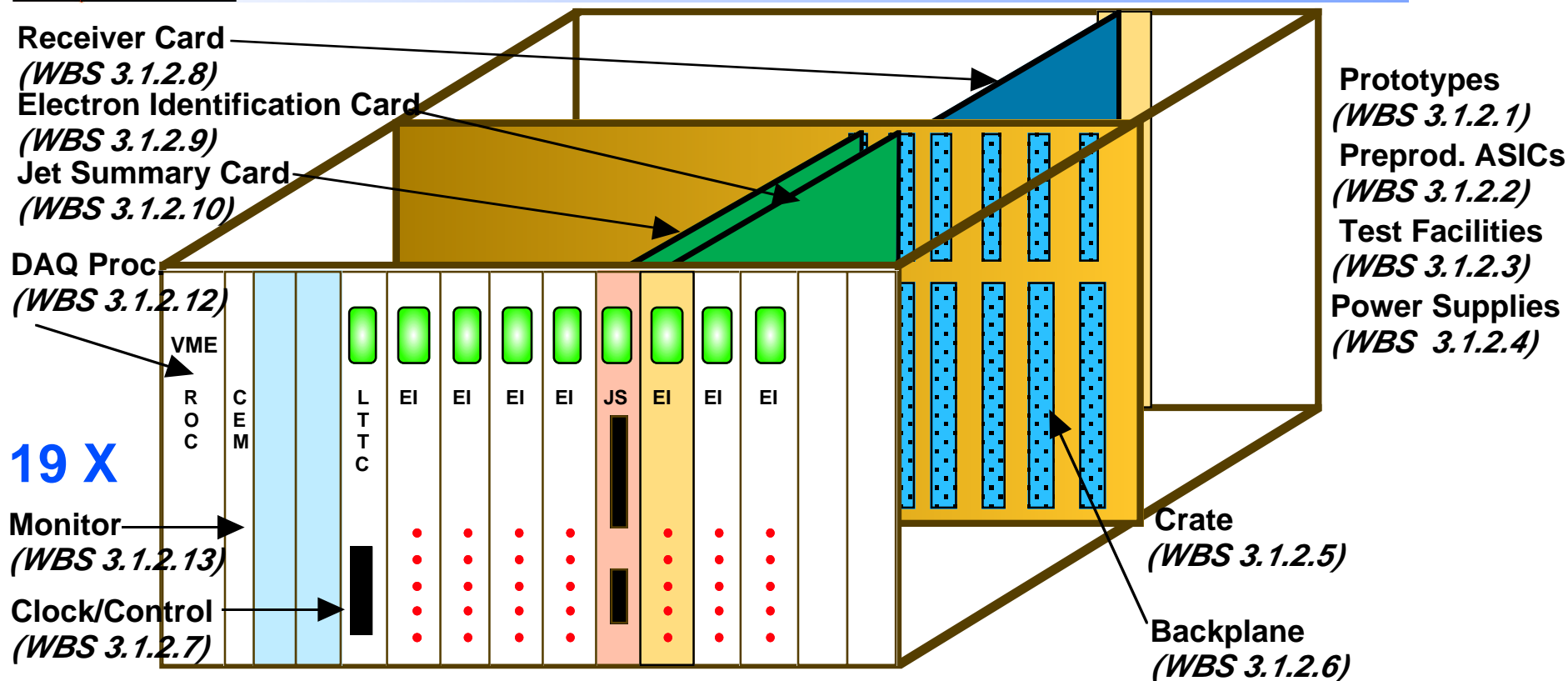
Calorimeter Regional Trigger Crate

Receiver Cards (x7/crate)



# Regional Calorimeter Crate

(WBS 3.1.2)



**Data from calorimeter FE on Cu links @ 1.2 Gbaud (ptyp. tstd.)**

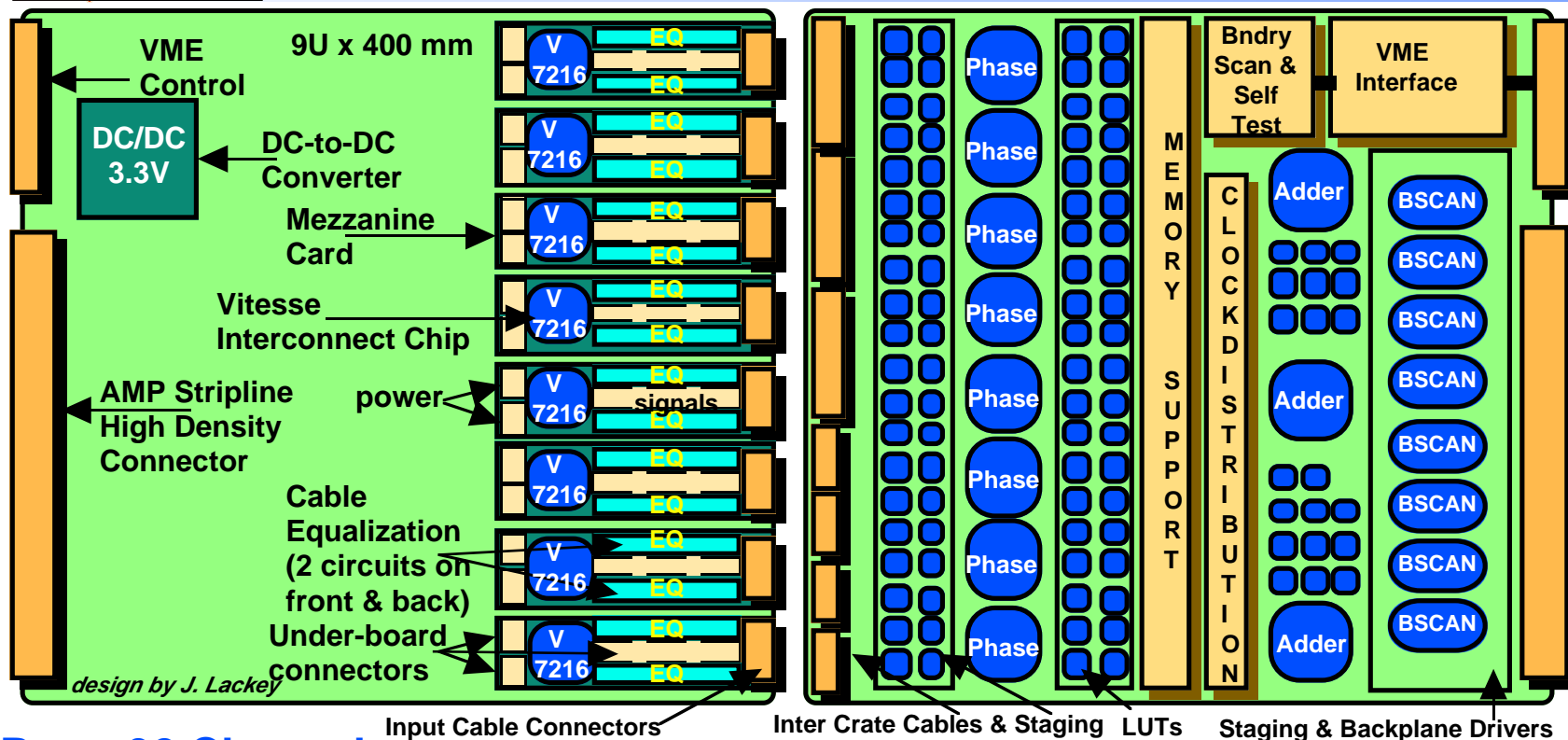
- Into 133 rear-mounted Receiver Cards (ptyp. tstd. w/ ASICs)

**160 MHz point to point backplane (ptyp. tstd.)**

- 19 Clock&Control (ptyp. tstd.), 133 Electron ID (ptyp. tstd.)
- 19 Jet/Summary, Receiver Cards operate @ 160 MHz



# Receiver Card



**Rear: 32 Channels =**

4 Ch. x 8 mezzanine cards

1.2 GBaud copper rcvrs

18 bit (2x9) data + 5 bit error

**Vitesse Chip:**

Converts Serial to Parallel  
Data to front at 120 MHz TTL

**Front: Phase ASIC: Deskew, Mux @ 160MHz**

Error bit for each 4x4, Test Vectors

**Memory LUT @ 160 MHz**

Linearization and  $e/\gamma$  &  $\tau$  veto bits

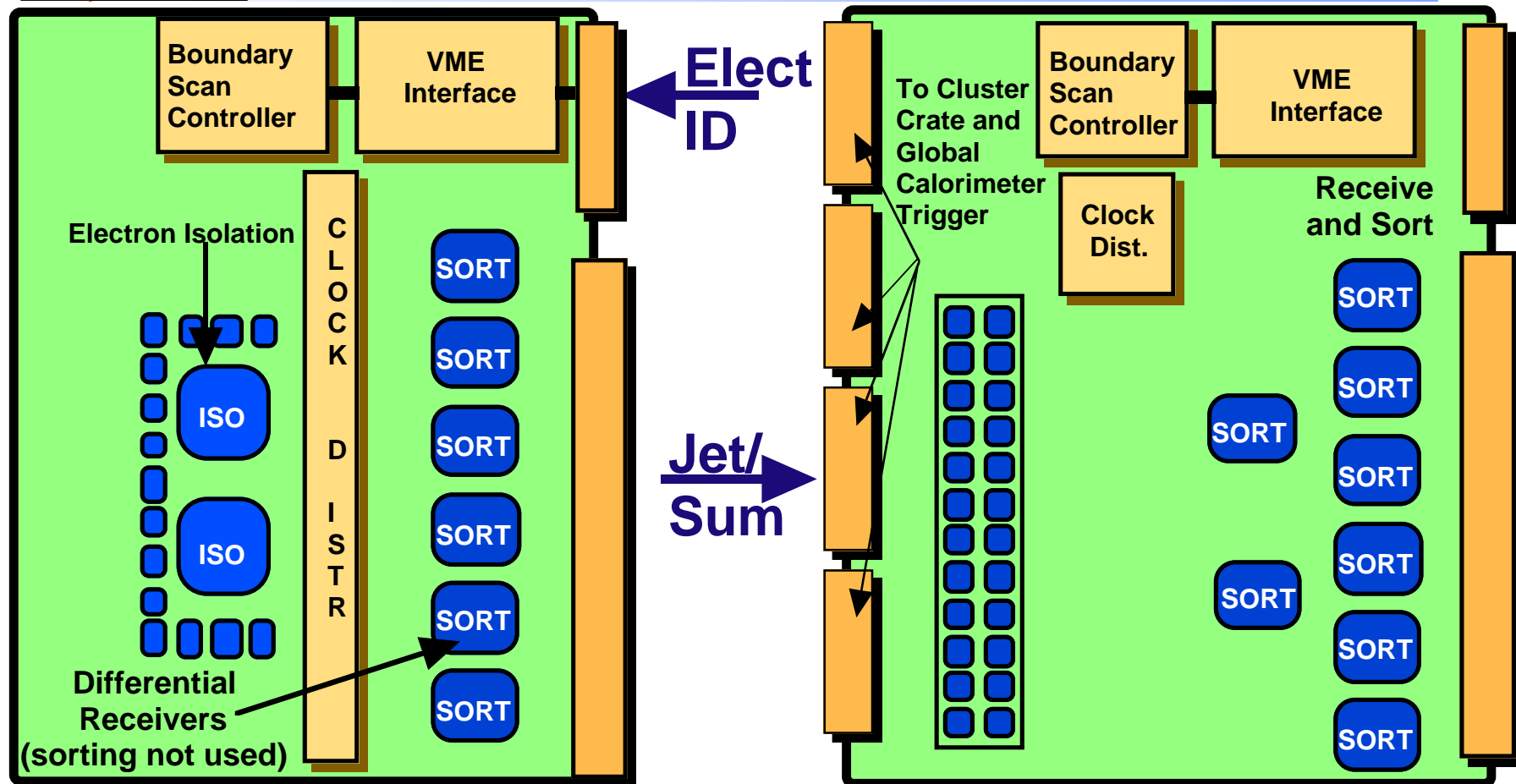
**Adder ASIC:**

8 inputs @ 160 MHz in 25 ns.

**Differential Output @ 160 MHz**



# Electron ID & Jet/Summary Cards



**Processes 4x8 region @ 160 MHz**  
**Electron isolation on ASIC**  
**Lookup tables for ranking**  
**Takes Max in each 4x4**

**Summarizes full crate:**  
**Sorts 14 iso. e's → top 4 iso e's**  
**Sorts 14 non. iso e's → top 4 non iso e's**  
**Stages 4x4  $E_T$  sums to cluster crate**  
**Iso, non iso e's and Quiet/Minl bits to GCT**



# Jet/ $\tau$ Cluster and HF Crates

## Jet/ $\tau$ Clustering

- **New algorithms to seamlessly cover all  $\eta$ - $\phi$** 
  - New CMS physics requirement
- **HF Crate**
  - Uses portion of Receiver and Jet/Summary card functions
    - Vitesse serial links
    - Look Up Tables for linearization
    - Drive parallel differential signals to external crate
  - May be able to integrate in Jet/Summary card
- **Cluster Crate with proven RCT technology**
  - Parallel differential signal input for all  $\eta$ - $\phi$
  - Custom backplane for data sharing
  - Reuse ADDER, BSCAN & SORT ASICs for processing
  - All ECL logic with 160 MHz processing

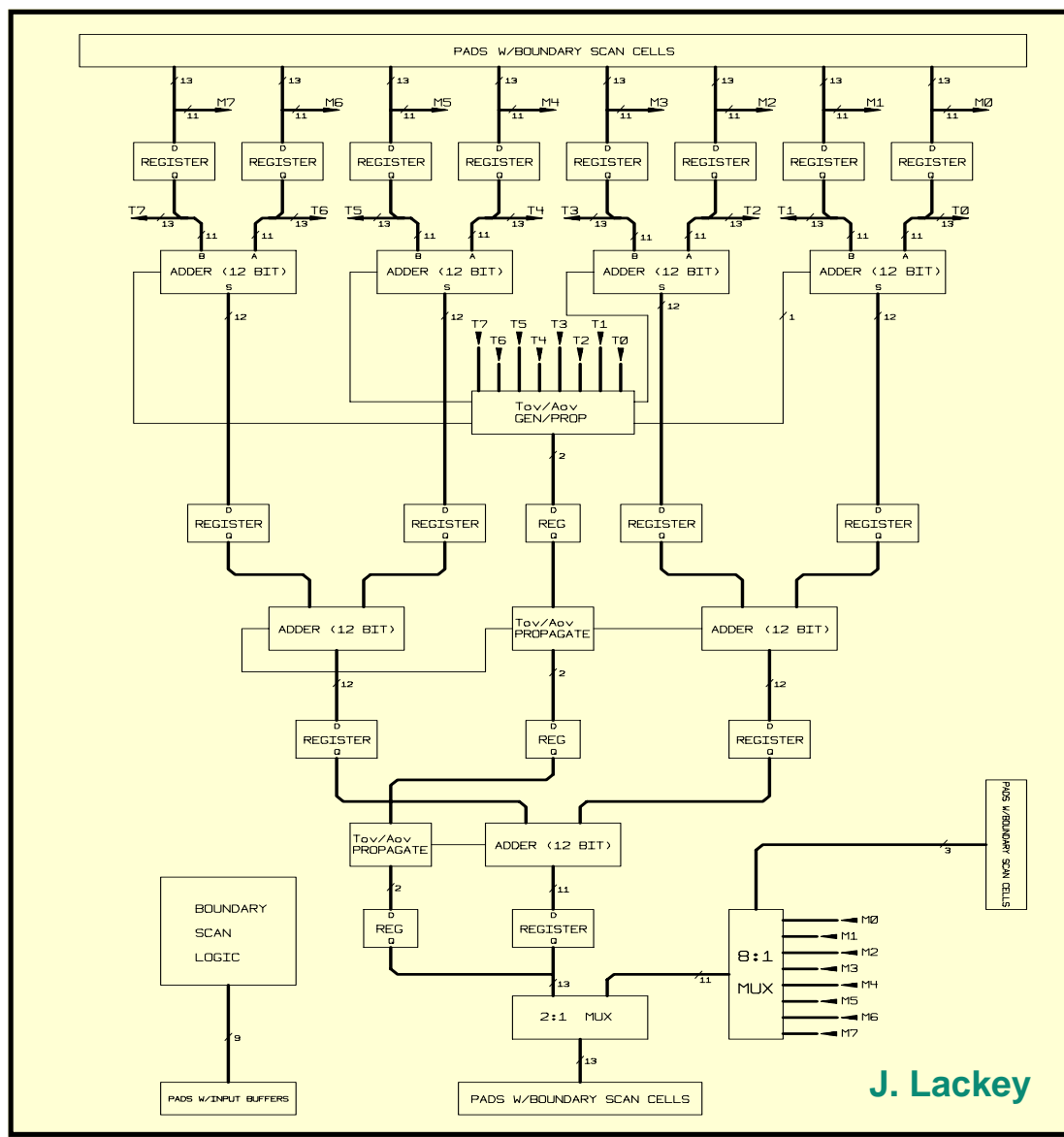




# 8 x 13-bit 160 MHz Adder ASIC

**Vitesse 0.6 $\mu$  H-GaAs  
Process: ECL I/O**

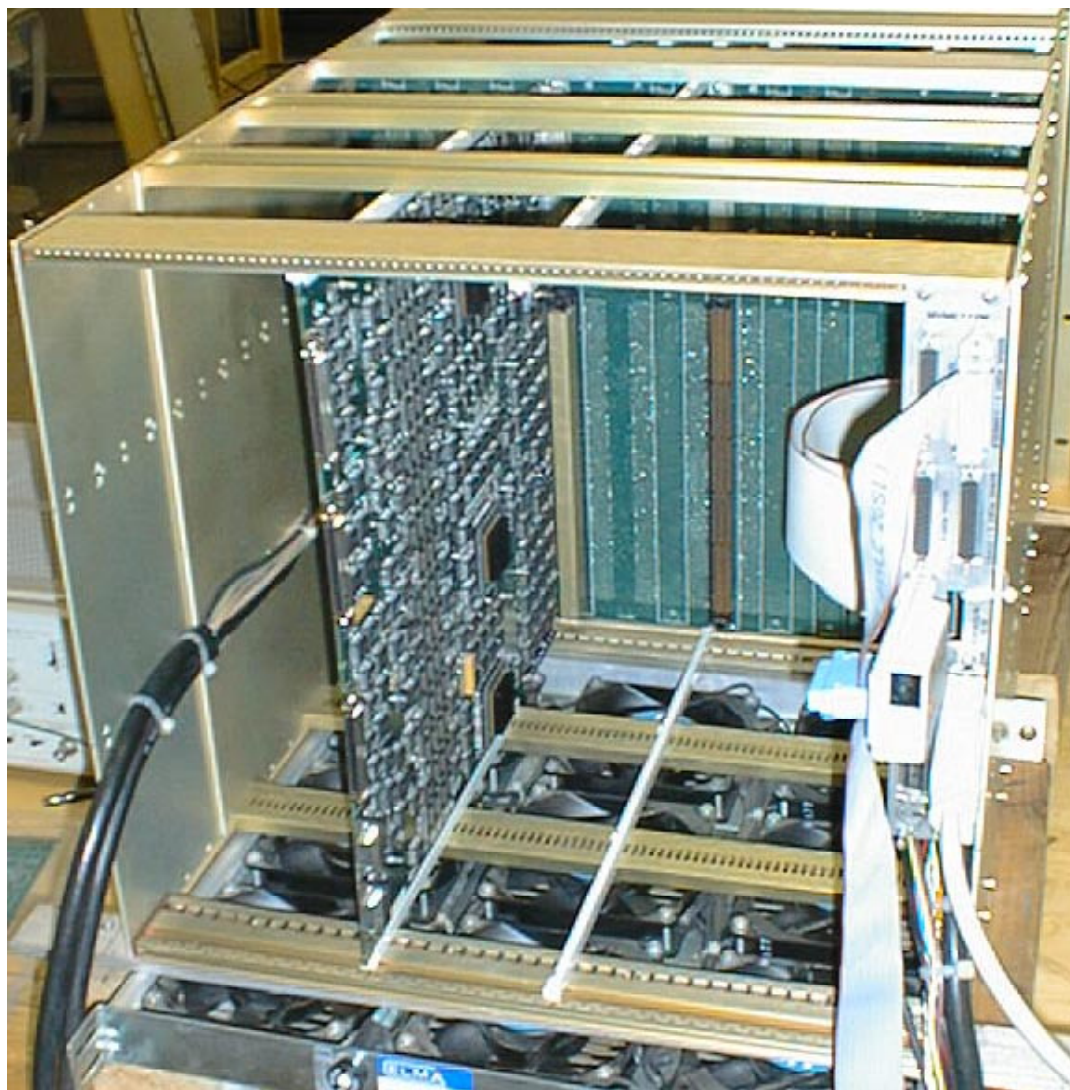
- 13 bits per operand  
x 8 operands
- Thirteen bit output
- Latency:  
25 ns @ 160 MHz
- Full Boundary Scan
- ~11,000 cells
- 4 Watts
- Tested > 200 MHz
- Operated on RC
- In Production



J. Lackey



# Cal. Trigger Dataflow Test

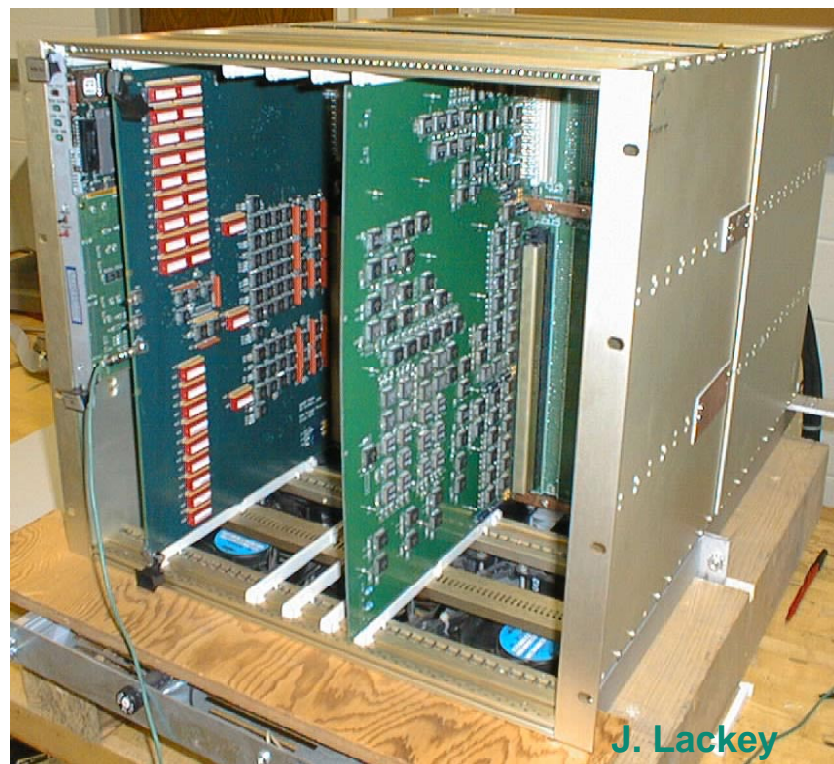


**REAR**

## Prototype Crate with

- 160 MHz Backplane
- Proto. Receiver Card (rear)
- Proto. Clock Card (front)
- Proto. Electron ID Card (front)

**Full 160 MHz dataflow verified**



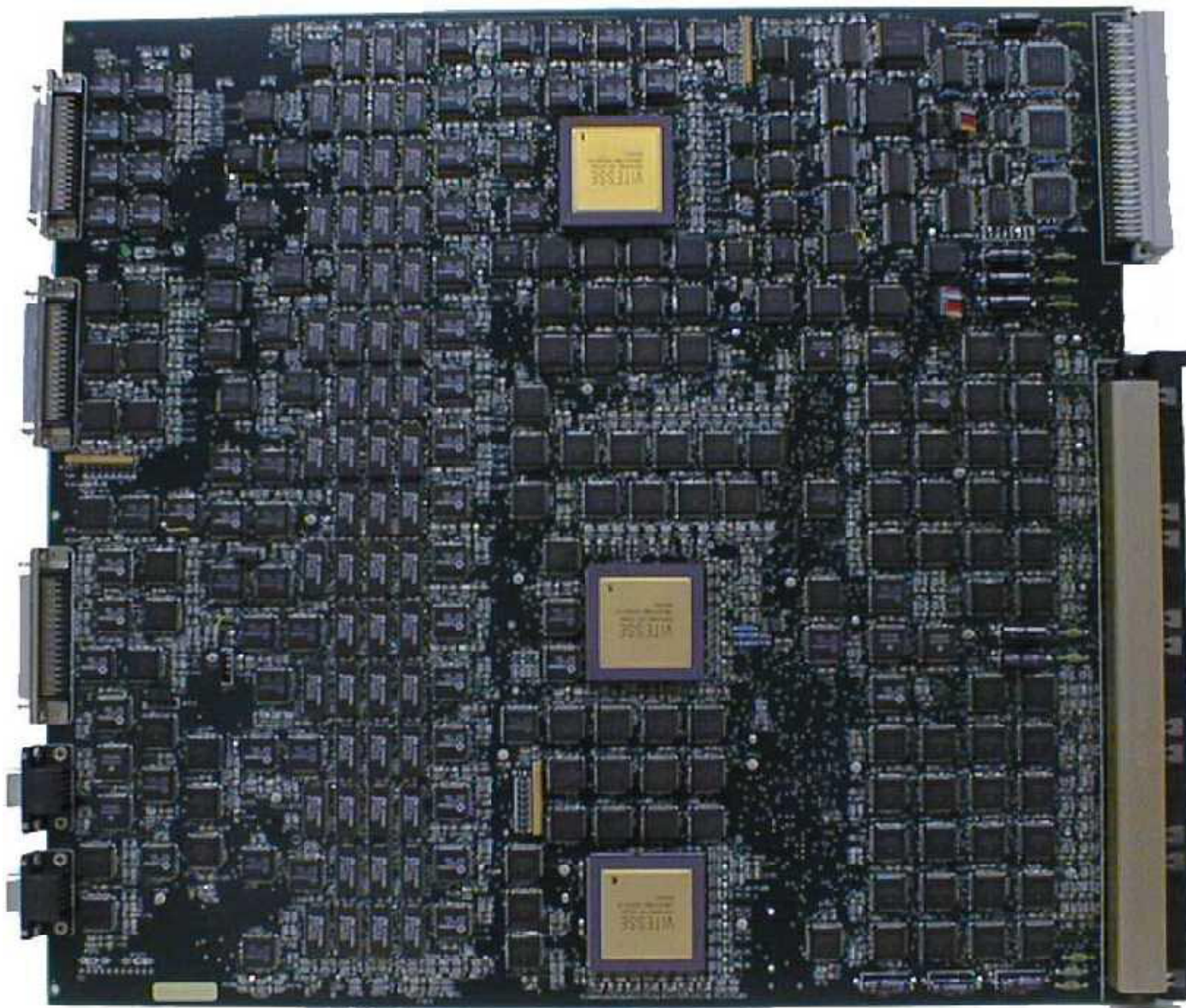
**FRONT**

J. Lackey  
M. Jaworski





# Prototype Receiver Card



**160 MHz  
Prototype  
Receiver  
Card tests:**

- VME Interface checked
- Adder ASIC's checked
- Timing checked
- Intercrate sharing checked

J. Lackey

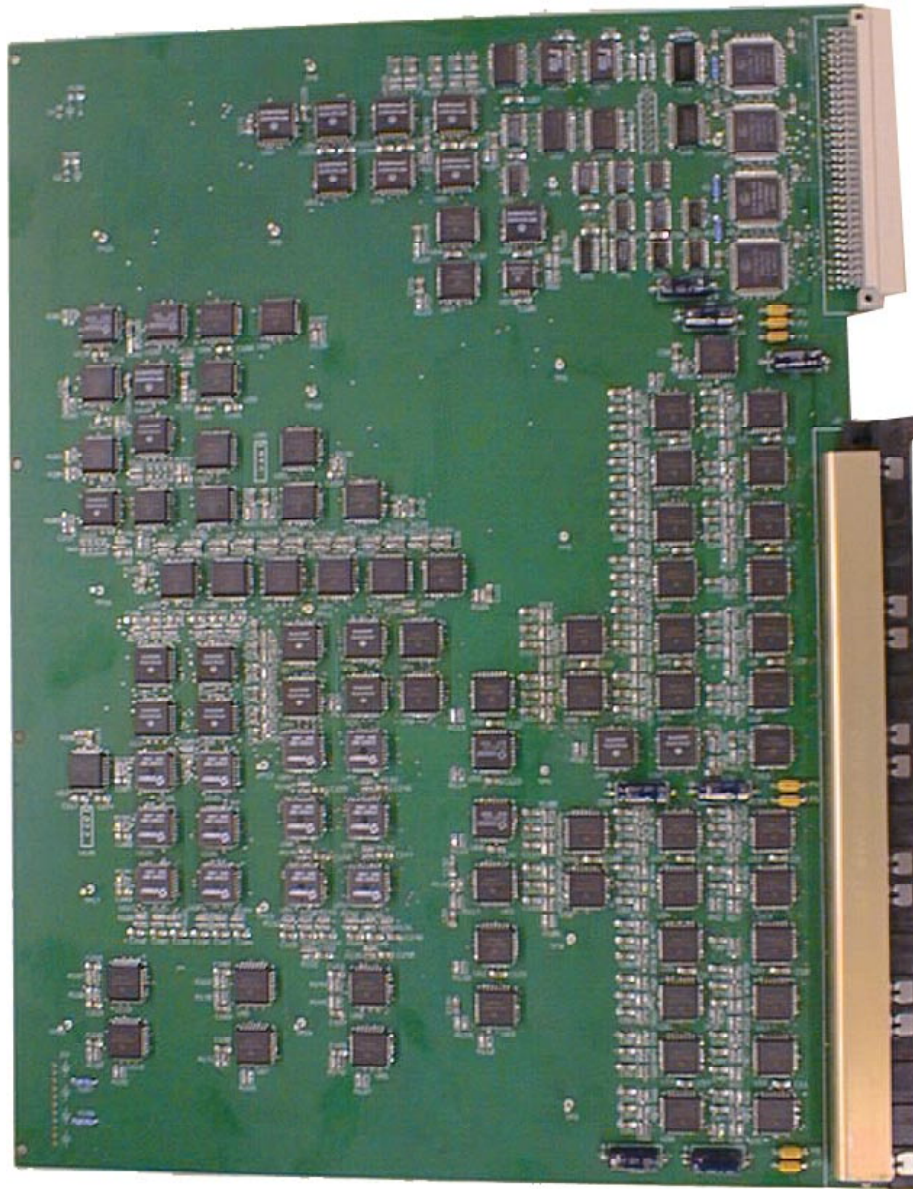


# Electron ID Card Prototype

## Card tested:

- VME Interface working
- Dataflow from Receiver Card through custom backplane works
- Timing checked
- Logic verified

J. Lackey







# ASIC Development - I

## Prototype Phase ASIC (Receiver Card)

J. Lackey

- Input: 120 MHz TTL data from Gbit Link Mezzanine Card
- Output: 160 MHz ECL data & error detection
- Status:
  - Full speed tests by Vitesse passed
  - Prototypes in hand for testing on our RC

## Prototype Boundary Scan ASIC (Receiver Card)

- Boundary scan of Receiver Card Input
- Backplane drivers -- compact circuitry
- Status:
  - Full speed tests by Vitesse passed
  - Prototypes in hand for testing on our RC

**Both ASICs placed on new Receiver Prototype**



# ASIC Development - II

## Electron ID ASIC (Electron ID Card)

J. Lackey

- Implements Electron Isolation algorithm
  - Described in talk of P. Chumney
- Status
  - Full speed tests by Vitesse passed
  - Prototypes in hand for testing on EIC

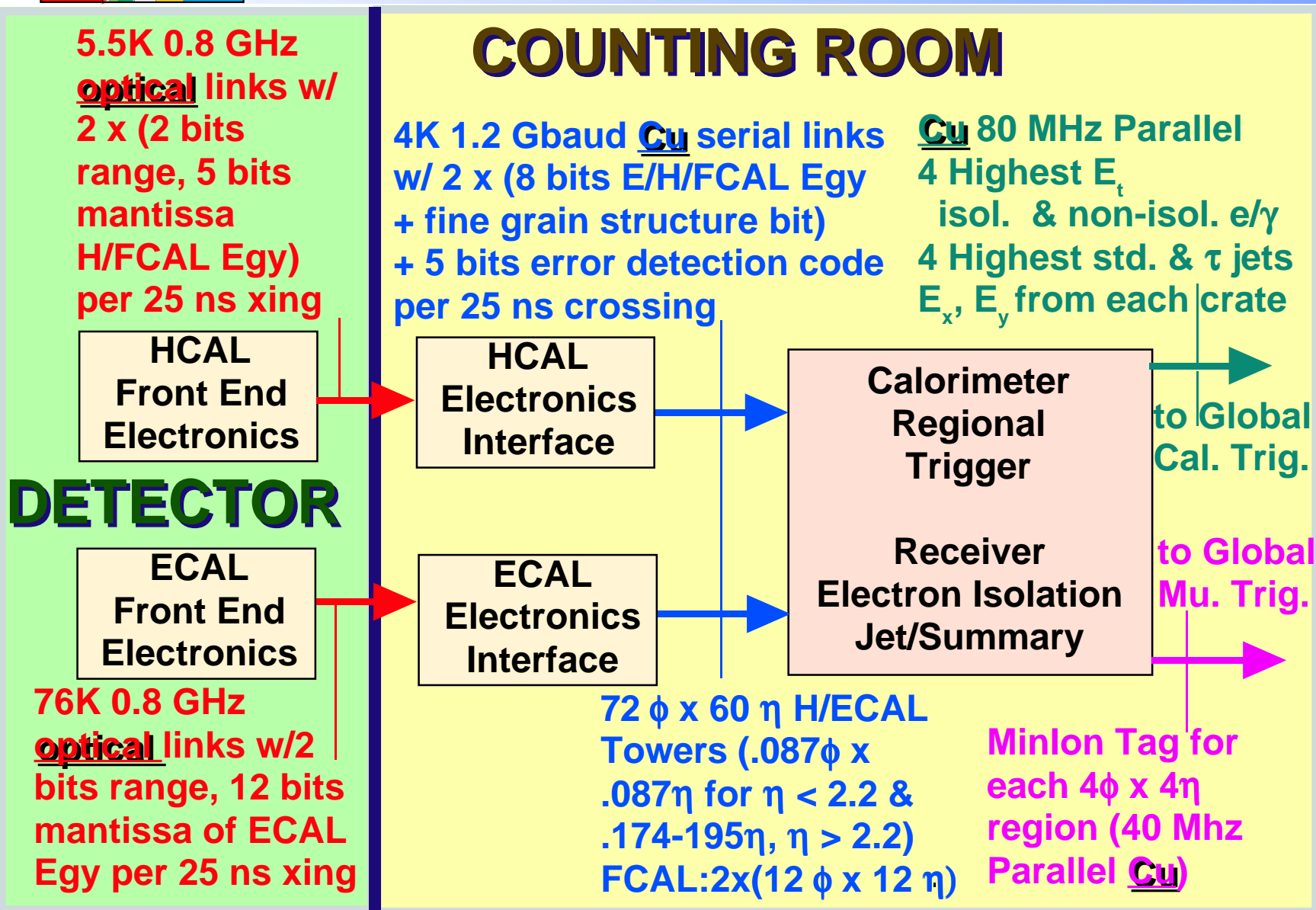
## Sort ASIC (EID & Jet/Summary Card)

- Integrated backplane receivers & sorting
  - Passes 4 highest rank of 32 inputs
  - Sorts input before passing unto card
- Status
  - Full speed tests by Vitesse passed
  - Prototypes in hand for testing on EIC

**Will test with new Electron ID Card prototype**

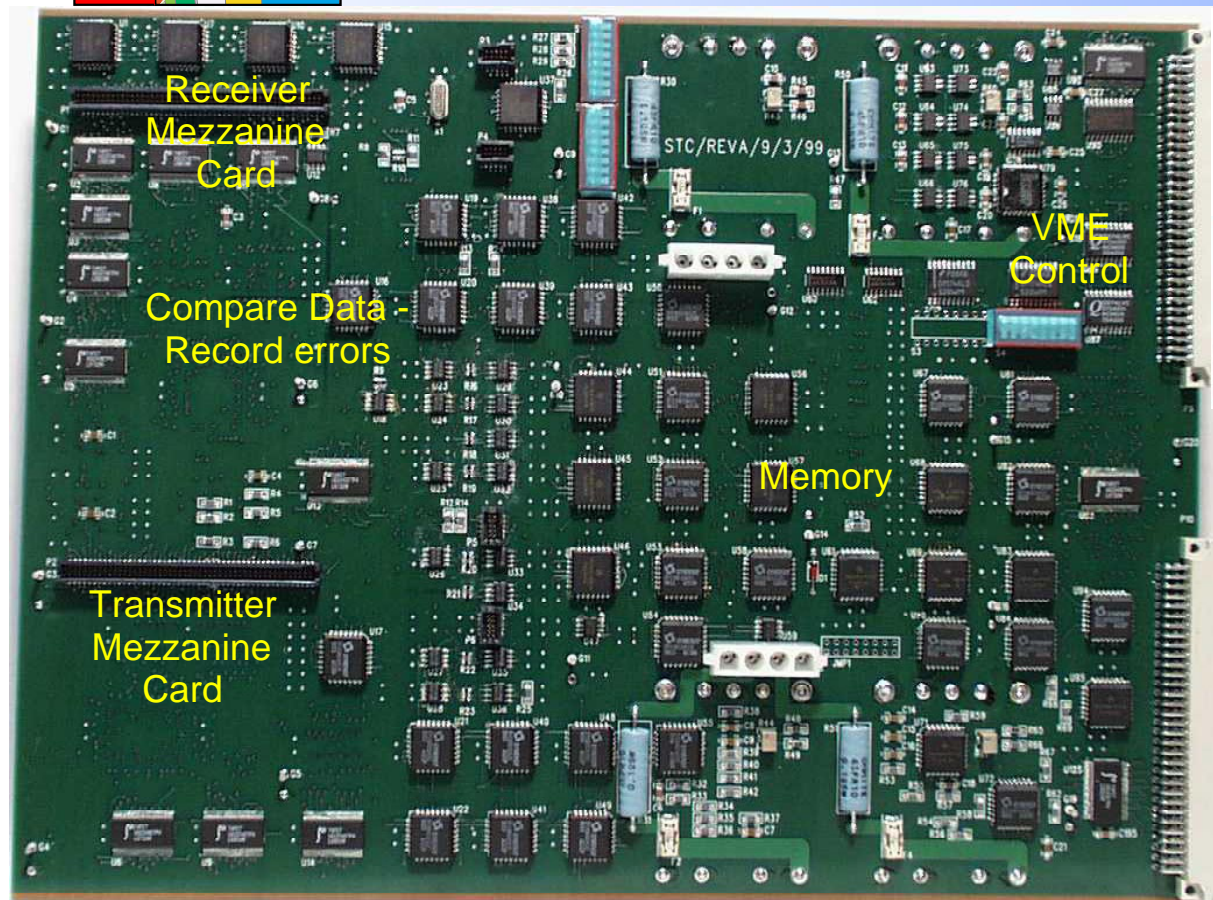


# Calorimeter Trigger Links





# Copper Cable Gbit Serial Data Tests



Receiver (top view)



Transmitter (top view)



Receiver (bottom view)



Transmitter (bottom view)

**Serial Link Test Card includes VME, memories & comparison circuitry to fully test serial links @ 120 MHz TTL from Mezzanine Cards. (U. Wisconsin)**

**Mezzanine Transmit & Receive Cards convert 4 x 1Gb/s links to 120 MHz TTL w/ Vitesse 7214 & cable equalization**

J. Lackey  
P. Robl  
D. Wahl

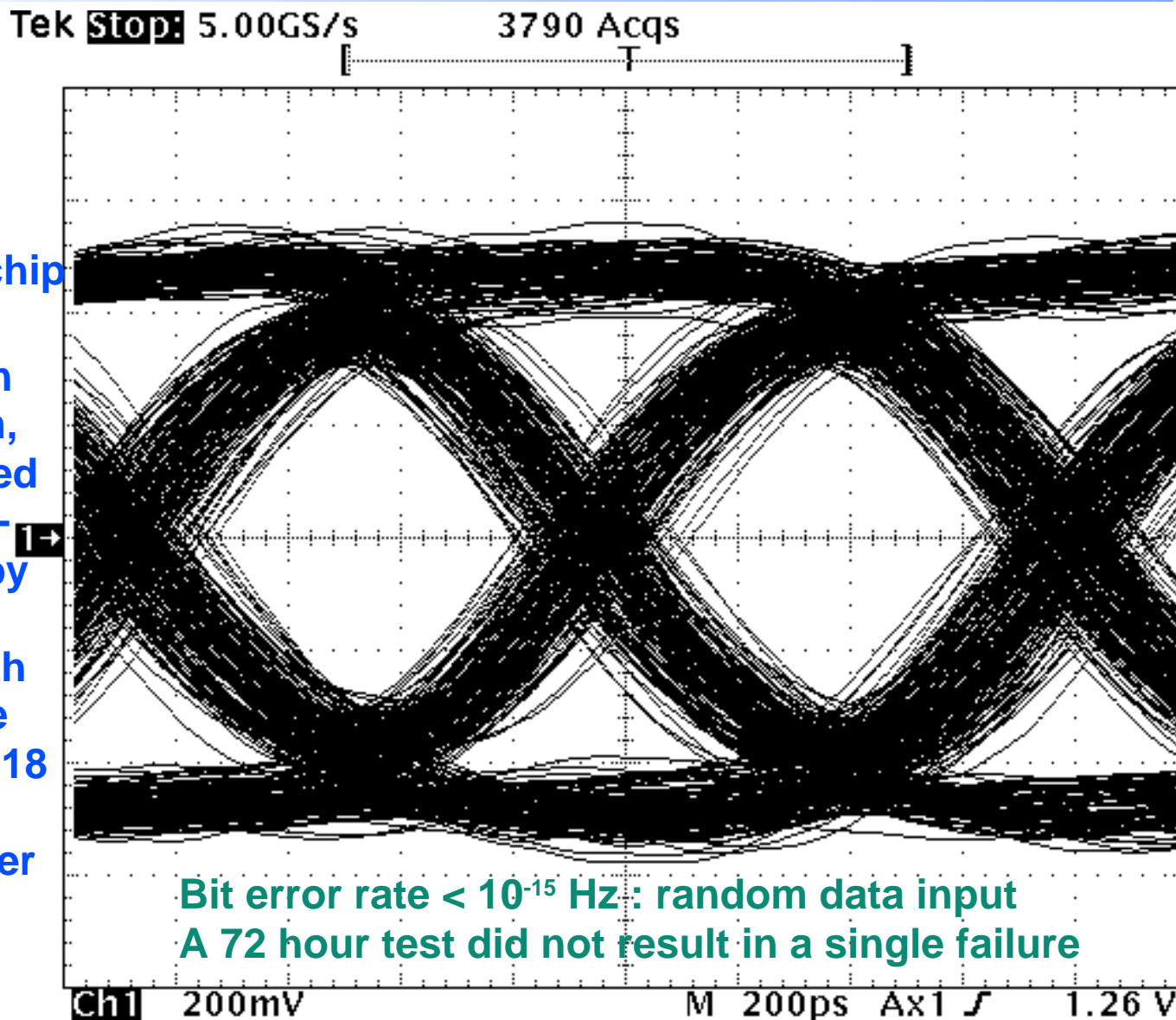




# GBit Data Transmission

## Tests over 20 m copper cable

- Vitesse 7214  
4 x Gigabit  
Interconnect chip
- twisted pair  
cables (Belden  
9182 (150 ohm,  
22AWG, foamed  
dielectric, twin-  
ax) grouped by  
fours &  
terminated with  
8-pin DIN style  
connectors \$318  
per 500 foot  
spool (\$2.10 per  
meter).



J. Lackey  
P. Robl



# Trigger Link Bit Error Detection

## Link error code simulation:

- **Between ECAL & HCAL Upper Level Readout & Cal. Regional Trigger**

- 2x(8 bits  $E_T$  + 1 bit finegrain)  
+ 5 bits error detection code\*  
+ 1 bit "Gap Flag" = 24 bits/25 ns
- Full 5-bit Hamming Code\* finds all 1 & 2-bit errors (most common)
- Also finds more than 96% of any other error type
- **Procedure upon error is to zero and log the error for readout by DAQ**
- **Full implementation in Phase ASIC**
  - Now integrated in Receiver card

| Bits with errors | Number of Patterns | Percent of Errors not found |
|------------------|--------------------|-----------------------------|
| 0                | 1                  | 0.00                        |
| 1                | 24                 | 0.00                        |
| 2                | 276                | 0.00                        |
| 3                | 2024               | 3.45                        |
| 4                | 10626              | 3.49                        |
| 5                | 42504              | 3.03                        |
| 6                | 134596             | 0.08                        |
| 7                | 346104             | 0.17                        |
| 8                | 735471             | 0.06                        |
| 9                | 1307504            | 0.14                        |
| 10               | 1961256            | 0.01                        |
| 11               | 2496144            | 0.01                        |
| 12               | 2704156            | 0.02                        |
| 13               | 2496144            | 0.01                        |
| 14               | 1961256            | 0.10                        |
| 15               | 1307504            | 0.15                        |
| 16               | 735471             | 0.06                        |
| 17               | 346104             | 0.30                        |
| 18               | 134596             | 0.08                        |
| 19               | 42504              | 3.24                        |
| 20               | 10626              | 3.23                        |
| 21               | 2024               | 2.77                        |
| 22               | 276                | 0.03                        |
| 23               | 24                 | 0.00                        |
| 24               | 1                  | 0.00                        |





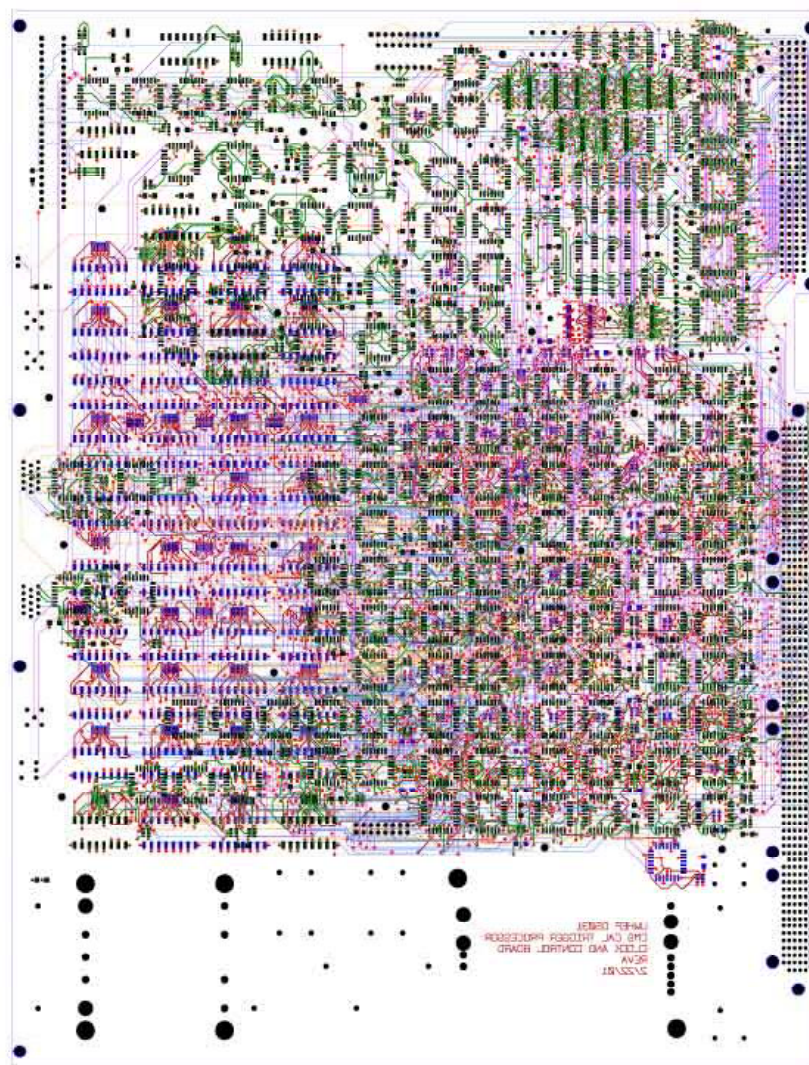
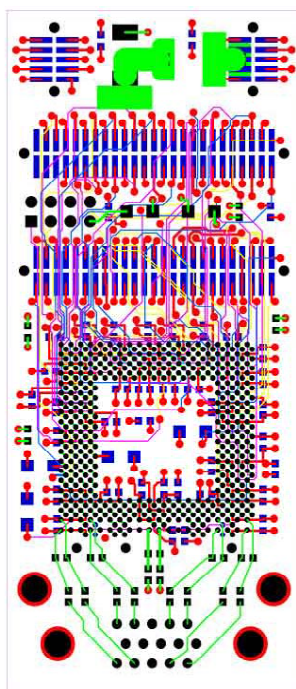
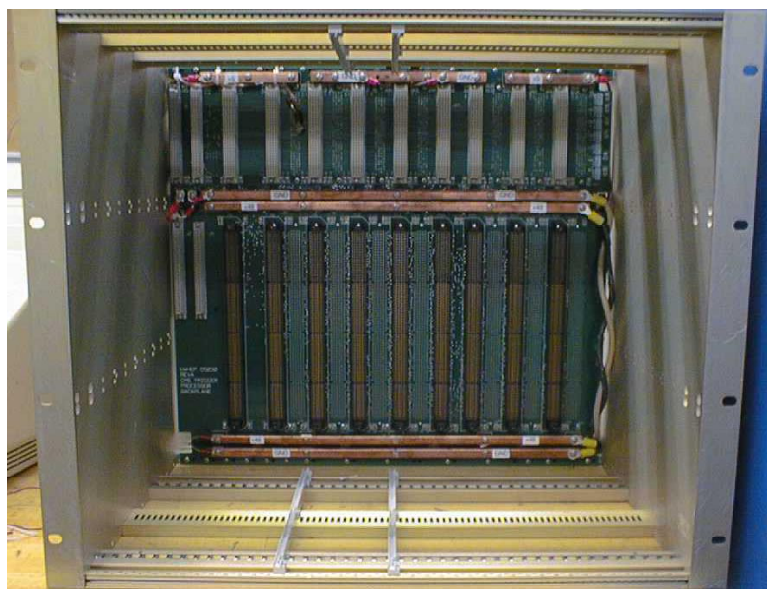
# Second Generation Prototypes

**Ready for tests**

- **Crate & Backplane**

**Ready for manufacture**

- **Clock & Control**
- **Serial Link mezzanine cards**





# Plans for This Year

## Crate & Backplane

- Ready for summer tests
- Assemble production versions after validation in summer

## Serial Links

- Finish new Serial Test Card (STC) for integration with E,HCAL
- New Mezz. card (w V7216) detailed validation on STC

## ASIC Procurement

- Complete order from Vitesse after summer tests

## Clock & Control, Receiver (RC) and Electron Isolation Cards (EIC)

- Finish design and manufacture 2nd generation prototypes
- Validate Serial Links, Phase & Boundary Scan ASICs on RC
- Validate Sort & Electron ID ASICs on EIC

## Jet/Summary Card

- Design first prototype - including output to cluster crate

## Cluster and HF crates

- Finalize designs



# Cal Trigger Personnel

## **Physicists** (at Wisconsin):

- Faculty: W. Smith & S. Dasu
- Ph.D. Physicists: P. Chumney & F. Di Lodovico

## **Engineers** (experienced team at Wisconsin):

- J. Lackey -- Lead Engineer & Designer
  - Also Lead Engineer for Zeus Calorimeter Trigger
- M. Jaworski -- Board Layout & Design support
  - Worked on Zeus Calorimeter Trigger
- R. Fobes -- Procurement and Assembly
  - Worked on Zeus Calorimeter Trigger
- P. Robl -- Copper Links & Design support
  - PSL Engineer, assisted by lead PSL electronics engineer, D. Wahl, who worked on Zeus Trigger



# Cal Trigger Production and Testing

## Electronics testing and remediation of manufacturing defects

- J. Lackey - Lead Engineer
- M. Jaworski, R. Fobes - Engineering Support
- P. Chumney - In charge of testing

## Software development (for tests and operation)

- Need professional team with real-time programming skills
  - Good post-doctoral project
  - CS or EE or suitably qualified physics graduate students

## Personnel is a concern

- Will need more people for production testing and software support
  - P. Chumney works on hardware at 50% level
    - Will supervise testing and develop software
  - Work with S. Dasu who has teaching responsibility now
  - Will need a crew for testing
    - ZEUS used 2 post-docs, 4 students for 2 years
- Base program support for post-doc and students necessary





# Conclusions

## Status

- Ready to test 2nd generation prototypes in summer
  - Crate and Backplane ready
  - ASICs ready, other parts procured
  - Clock & Control and Receiver Cards in final design
  - Electron Isolation Card in design
  - Serial Link Mezzanine Cards ready
  - Serial Link Test Card in final design

## Goals for this year

- Complete of prototype tests, validate & order ASICs
- Integrate Serial Links with ECAL, HCAL front-end
- Finalize Jet/Summary card design